Issue Classification



Application/Control No.

10750568

NGUYEN ET AL.

Applicant(s)/Patent Under Reexamination

Examiner

Art Unit

Kaplan, Hai I

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ORIGINAL							INTERNATIONAL CLASSIFICATION									
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Hal I. Kaplan 10/24/2007 (Assistant Examiner) (Date)			-	10/28/07						Total Claims Allowed:						
(Legal Instruments (Date) Examiner) L.S. Betont and Trademark Office					MICH SUPERVISOR (Primary Examiner)					AREL SHERRY RY PATENT EXAMINER (Date)			Clair	O.G. Print Figure		